

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination INNEMAN ET AL.	
		Examiner Allen C. Ho	Art Unit 2882	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,881,965 B2	04-2005	Bowen et al.	250/492.2
*	B	US-6,624,431 B1	09-2003	Foster et al.	250/505.1
*	C	US-6,587,538 B2	07-2003	Igarashi et al.	378/19
*	D	US-6,470,072 B1	10-2002	Johnson, Mark A.	378/154
*	E	US-6,438,210 B1	08-2002	Castleberry, Donald Earl	378/154
*	F	US-6,175,615 B1	01-2001	Guru et al.	378/149
*	G	US-6,055,296	04-2000	Ferlic et al.	378/154
*	H	US-5,799,057	08-1998	Hoffman et al.	378/147
*	I	US-5,727,044	03-1998	Fraser et al.	378/149
*	J	US-5,581,592	12-1996	Zarnoch et al.	378/154
*	K	US-5,459,771	10-1995	Richardson et al.	378/119
*	L	US-5,265,143	11-1993	Early et al.	378/84
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	B. D. Cullity and S. R. Stock. Elements of X-Ray Diffraction, third edition (Upper Saddle River, NJ: Prentice Hall, 2001), p. 194-197.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.